IN THE SPECIFICATION:

Page 1, after the heading "DESCRIPTION" please insert the following:

-- RELATED APPLICATIONS

This application is a divisional application of U.S. application Serial No. 09/519,897, filed on March 6, 2000.--

IN THE CLAIMS:

Please cancel Claims 1-22, without prejudice or disclaimer, and add the following new claims:

- --25. The electrical contact of Claim 23 wherein said silicon-containing semiconductor material comprises single crystal Si, polycrystalline Si, SiGe, amorphous Si or a silicon-on-insulator (SOI).
- 26. The electrical contact of Claim 23 wherein said metal of said disilicide is Co and said metal silicide is Co disilicide.
- 27. The electrical contact of Claim 23 wherein said metal of said disilicide is Ti and said metal silicide is TiSi₂.
 - 28. The electrical contact of Claim 27 wherein said TiSi₂ is in the C54 phase.
- 29. The electrical contact of Claim 23 further comprising an oxide layer present near a surface of said substrate.
- 30. The electrical contact of Claim 29 wherein said oxide layer has a thickness of from about 0.1 to about 3.0 nm.
 - 31. The electrical contact of Claim 23 wherein said substrate is doped.